Application/Control No.	Applicant(s)/Patent under Reexamination	
10/774,594	CHEN ET AL.	
Examiner	Art Unit	
Mark A. X Radtke	2165	

SEARCHED					
Subclass	Date	Examiner			
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	Subclass	Subclass Date			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
•	DATE	EXMR		
Consulted Primary Examiner Sam Rimell regarding 132 affidavits	4/11/2007	MAXR		
Searched EAST	11/16/2007	MAXR		
Double patenting search	11/16/2007	MAXR		
Searched Google, Google Scholar, ACM, IEEE	11/16/2007	MAXR		
See print out of search history	11/16/2007	MAXR		